

Welcome to [E-XFL.COM](https://www.e-xfl.com)

Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	2560
Number of I/O	202
Number of Gates	54000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	272-BBGA
Supplier Device Package	272-PBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx36-1bgg272

Tables

Table 1	Product profile	1
Table 2	Plastic Device Resources	4
Table 3	Ceramic Device Resources	4
Table 4	Temperature Grade Offerings	5
Table 5	Speed Grade Offerings	5
Table 6	Voltage Support of MX Devices	13
Table 7	Fixed Capacitance Values for MX FPGAs (pF)	16
Table 8	Device Configuration Options for Probe Capability	17
Table 9	Test Access Port Descriptions	18
Table 10	Supported BST Public Instructions	18
Table 11	Boundary Scan Pin Configuration and Functionality	19
Table 12	Absolute Maximum Ratings for 40MX Devices*	20
Table 13	Absolute Maximum Ratings for 42MX Devices*	20
Table 14	Recommended Operating Conditions	21
Table 15	5V TTL Electrical Specifications	21
Table 16	Absolute Maximum Ratings for 40MX Devices*	22
Table 17	Absolute Maximum Ratings for 42MX Devices*	22
Table 18	Recommended Operating Conditions	22
Table 19	3.3V LVTTTL Electrical Specifications	23
Table 20	Absolute Maximum Ratings*	23
Table 21	Recommended Operating Conditions	24
Table 22	Mixed 5.0V/3.3V Electrical Specifications	25
Table 23	DC Specification (5.0 V PCI Signaling)	25
Table 24	AC Specifications (5.0V PCI Signaling)*	26
Table 25	DC Specification (3.3 V PCI Signaling)	27
Table 26	AC Specifications for (3.3 V PCI Signaling)*	27
Table 27	Package Thermal Characteristics	29
Table 28	42MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^{\circ}\text{C}$, $V_{CCA} = 5.0\text{ V}$)	38
Table 29	40MX Temperature and Voltage Derating Factors(Normalized to $T_J = 25^{\circ}\text{C}$, $V_{CC} = 5.0\text{ V}$)	38
Table 30	42MX Temperature and Voltage Derating Factors(Normalized to $T_J = 25^{\circ}\text{C}$, $V_{CCA} = 3.3\text{ V}$)	39
Table 31	40MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^{\circ}\text{C}$, $V_{CC} = 3.3\text{ V}$)	39
Table 32	Clock Specification for 33 MHz PCI	40
Table 33	Timing Parameters for 33 MHz PCI	40
Table 34	A40MX02 Timing Characteristics (Nominal 5.0 V Operation)	41
Table 35	A40MX02 Timing Characteristics (Nominal 3.3 V Operation)	43
Table 36	A40MX04 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, $V_{CC} = 4.75\text{ V}$, $T_J = 70^{\circ}\text{C}$)	46
Table 37	A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, $V_{CC} = 3.0\text{ V}$, $T_J = 70^{\circ}\text{C}$)	49
Table 38	A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, $V_{CCA} = 4.75\text{ V}$, $T_J = 70^{\circ}\text{C}$)	52
Table 39	A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, $V_{CCA} = 3.0\text{ V}$, $T_J = 70^{\circ}\text{C}$)	56
Table 40	A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, $V_{CCA} = 4.75\text{ V}$, $T_J = 70^{\circ}\text{C}$)	60
Table 41	A42MX16 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, $V_{CCA} = 3.0\text{ V}$, $T_J = 70^{\circ}\text{C}$)	64
Table 42	A42MX24 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, $V_{CCA} = 4.75\text{ V}$, $T_J = 70^{\circ}\text{C}$)	67
Table 43	A42MX24 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, $V_{CCA} = 3.0\text{ V}$, $T_J = 70^{\circ}\text{C}$)	71
Table 44	A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, $V_{CCA} = 4.75\text{ V}$, $T_J = 70^{\circ}\text{C}$)	75
Table 45	A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions,	

3 40MX and 42MX FPGAs

3.1 General Description

Microsemi's 40MX and 42MX families offer a cost-effective design solution at 5V. The MX devices are single-chip solutions and provide high performance while shortening the system design and development cycle. MX devices can integrate and consolidate logic implemented in multiple PALs, CPLDs, and FPGAs. Example applications include high-speed controllers and address decoding, peripheral bus interfaces, DSP, and co-processor functions.

The MX device architecture is based on Microsemi's patented antifuse technology implemented in a 0.45µm triple-metal CMOS process. With capacities ranging from 3,000 to 54,000 system gates, the MX devices provide performance up to 250 MHz, are live on power-up and have one-fifth the standby power consumption of comparable FPGAs. MX FPGAs provide up to 202 user I/Os and are available in a wide variety of packages and speed grades.

A42MX24 and A42MX36 devices also feature multiPlex I/Os, which support mixed-voltage systems, enable programmable PCI, deliver high-performance operation at both 5.0V and 3.3V, and provide a low-power mode. The devices are fully compliant with the PCI local bus specification (version 2.1). They deliver 200 MHz on-chip operation and 6.1 ns clock-to-output performance.

The 42MX24 and 42MX36 devices include system-level features such as IEEE Standard 1149.1 (JTAG) Boundary Scan Testing and fast wide-decode modules. In addition, the A42MX36 device offers dual-port SRAM for implementing fast FIFOs, LIFOs, and temporary data storage. The storage elements can efficiently address applications requiring wide data path manipulation and can perform transformation functions such as those required for telecommunications, networking, and DSP.

All MX devices are fully tested over automotive and military temperature ranges. In addition, the largest member of the family, the A42MX36, is available in both CQ208 and CQ256 ceramic packages screened to MIL-STD-883 levels. For easy prototyping and conversion from plastic to ceramic, the CQ208 and PQ208 devices are pin-compatible.

3.2 MX Architectural Overview

The MX devices are composed of fine-grained building blocks that enable fast, efficient logic designs. All devices within these families are composed of logic modules, I/O modules, routing resources and clock networks, which are the building blocks for fast logic designs. In addition, the A42MX36 device contains embedded dual-port SRAM modules, which are optimized for high-speed data path functions such as FIFOs, LIFOs and scratch pad memory. A42MX24 and A42MX36 also contain wide-decode modules.

3.2.1 Logic Modules

The 40MX logic module is an eight-input, one-output logic circuit designed to implement a wide range of logic functions with efficient use of interconnect routing resources.(see the following figure).

The logic module can implement the four basic logic functions (NAND, AND, OR and NOR) in gates of two, three, or four inputs. The logic module can also implement a variety of D-latches, exclusivity functions, AND-ORs and OR-ANDs. No dedicated hard-wired latches or flip-flops are required in the array; latches and flip-flops can be constructed from logic modules whenever required in the application.

Silicon Sculptor programs devices independently to achieve the fastest programming times possible. After being programmed, each fuse is verified to insure that it has been programmed correctly. Furthermore, at the end of programming, there are integrity tests that are run to ensure no extra fuses have been programmed. Not only does it test fuses (both programmed and non-programmed), Silicon Sculptor also allows self-test to verify its own hardware extensively.

The procedure for programming an MX device using Silicon Sculptor is as follows:

1. Load the *.AFM file
2. Select the device to be programmed
3. Begin programming

When the design is ready to go to production, Microsemi offers device volume-programming services either through distribution partners or via In-House Programming from the factory.

For more details on programming MX devices, see the *AC225: Programming Antifuse Devices* application note and the *Silicon Sculptor 3 Programmers User Guide*.

3.3.4 Power Supply

MX devices are designed to operate in both 5.0V and 3.3V environments. In particular, 42MX devices can operate in mixed 5.0 V/3.3 V systems. The following table describes the voltage support of MX devices.

Table 6 • Voltage Support of MX Devices

Device	VCC	VCCA	VCCI	Maximum Input Tolerance	Nominal Output Voltage
40MX	5.0 V	–	–	5.5 V	5.0 V
	3.3 V	–	–	3.6 V	3.3 V
42MX	–	5.0 V	5.0 V	5.5 V	5.0 V
	–	3.3 V	3.3 V	3.6 V	3.3 V
	–	5.0 V	3.3 V	5.5 V	3.3 V

For A42MX24 and A42MX36 devices the VCCA supply has to be monotonic during power up in order for the POR to issue reset to the JTAG state machine correctly. For more information, see the *AC291: 42MX Family Devices Power-Up Behavior*.

3.3.5 Power-Up/Down in Mixed-Voltage Mode

When powering up 42MX in mixed voltage mode (VCCA = 5.0 V and VCCI = 3.3 V), VCCA must be greater than or equal to VCCI throughout the power-up sequence. If VCCI exceeds VCCA during power-up, one of two things will happen:

- The input protection diode on the I/Os will be forward biased
- The I/Os will be at logical High

In either case, ICC rises to high levels. For power-down, any sequence with VCCA and VCCI can be implemented.

3.3.6 Transient Current

Due to the simultaneous random logic switching activity during power-up, a transient current may appear on the core supply (VCC). Customers must use a regulator for the VCC supply that can source a minimum of 100 mA for transient current during power-up. Failure to provide enough power can prevent the system from powering up properly and result in functional failure. However, there are no reliability concerns, since transient current is distributed across the die instead of confined to a localized spot.

Since the transient current is not due to I/O switching, its value and duration are independent of the VCCI.

f_{q2} = Average second routed array clock rate in MHz)

Table 7 • Fixed Capacitance Values for MX FPGAs (pF)

Device Type	r1 routed_Clk1	r2 routed_Clk2
A40MX02	41.4	N/A
A40MX04	68.6	N/A
A42MX09	118	118
A42MX16	165	165
A42MX24	185	185
A42MX36	220	220

3.4.6 Test Circuitry and Silicon Explorer II Probe

MX devices contain probing circuitry that provides built-in access to every node in a design, via the use of Silicon Explorer II. Silicon Explorer II is an integrated hardware and software solution that, in conjunction with the Designer software, allow users to examine any of the internal nets of the device while it is operating in a prototyping or a production system. The user can probe into an MX device without changing the placement and routing of the design and without using any additional resources. Silicon Explorer II's noninvasive method does not alter timing or loading effects, thus shortening the debug cycle and providing a true representation of the device under actual functional situations.

Silicon Explorer II samples data at 100 MHz (asynchronous) or 66 MHz (synchronous). Silicon Explorer II attaches to a PC's standard COM port, turning the PC into a fully functional 18-channel logic analyzer. Silicon Explorer II allows designers to complete the design verification process at their desks and reduces verification time from several hours per cycle to a few seconds.

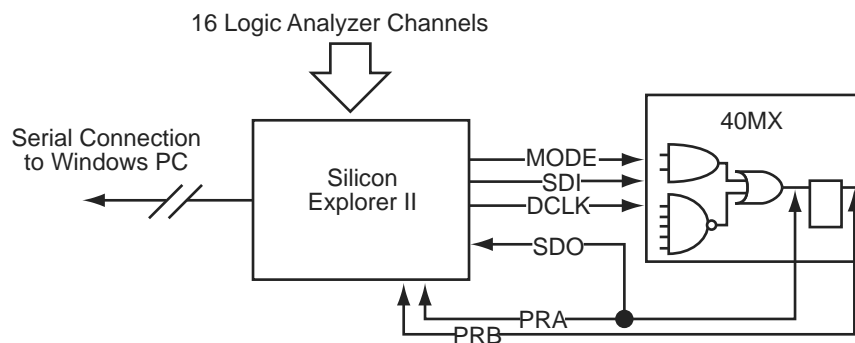
Silicon Explorer II is used to control the MODE, DCLK, SDI and SDO pins in MX devices to select the desired nets for debugging. The user simply assigns the selected internal nets in the Silicon Explorer II software to the PRA/PRB output pins for observation. Probing functionality is activated when the MODE pin is held HIGH.

Figure 12, page 16 illustrates the interconnection between Silicon Explorer II and 40MX devices, while Figure 13, page 17 illustrates the interconnection between Silicon Explorer II and 42MX devices

To allow for probing capabilities, the security fuses must not be programmed. (See User Security, page 12 for the security fuses of 40MX and 42MX devices). Table 8, page 17 summarizes the possible device configurations for probing.

PRA and PRB pins are dual-purpose pins. When the "Reserve Probe Pin" is checked in the Designer software, PRA and PRB pins are reserved as dedicated outputs for probing. If PRA and PRB pins are required as user I/Os to achieve successful layout and "Reserve Probe Pin" is checked, the layout tool will override the option and place user I/Os on PRA and PRB pins.

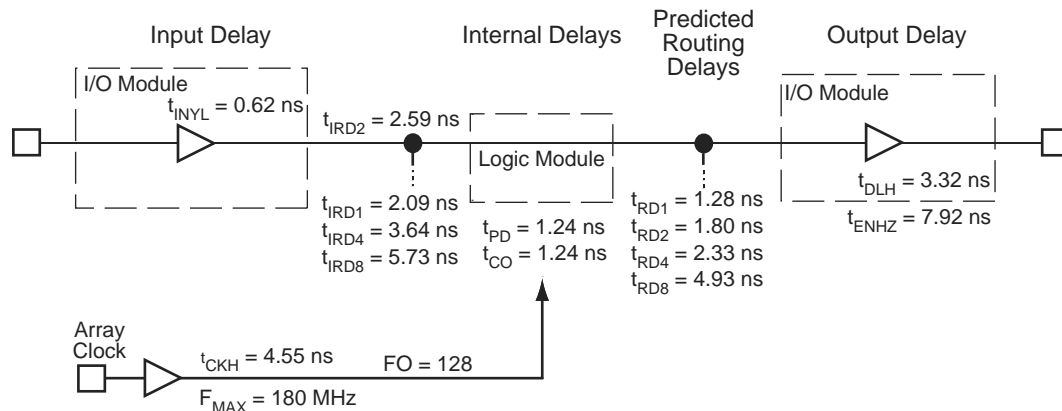
Figure 12 • Silicon Explorer II Setup with 40MX



3.10 Timing Models

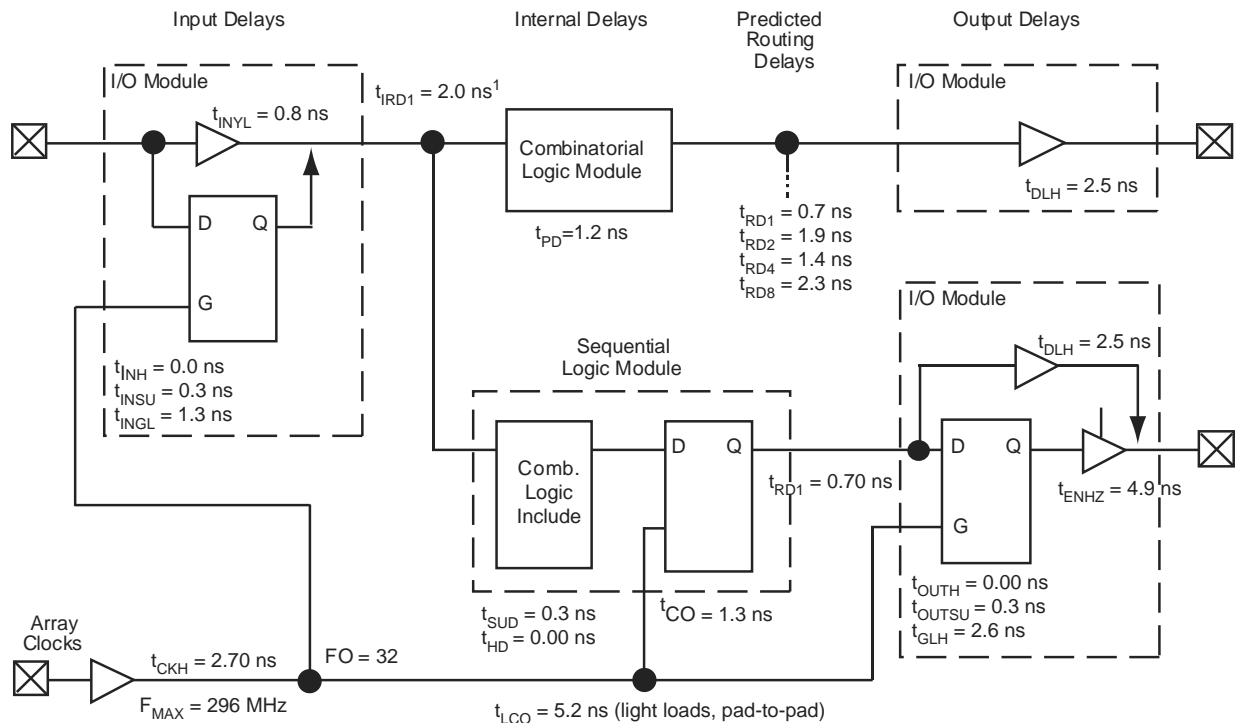
The following figures show various timing models.

Figure 17 • 40MX Timing Model*



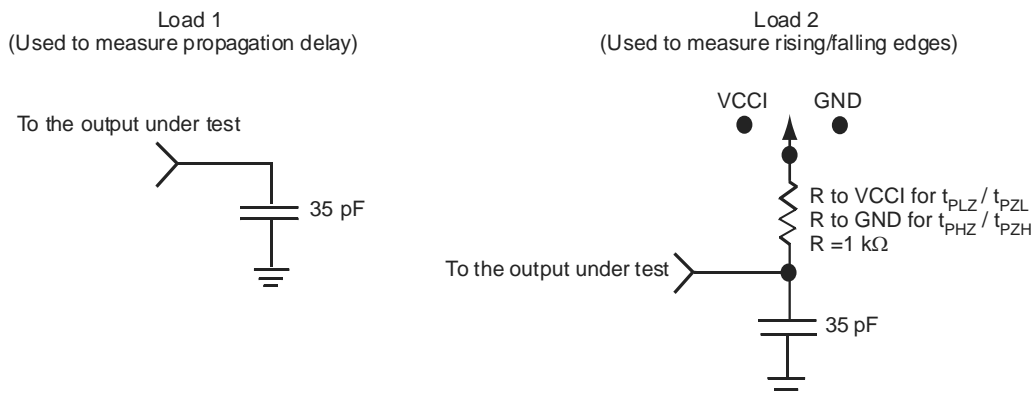
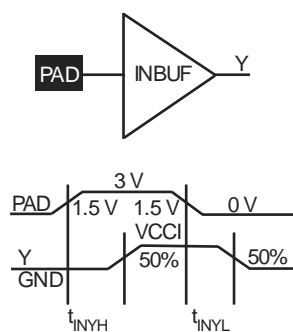
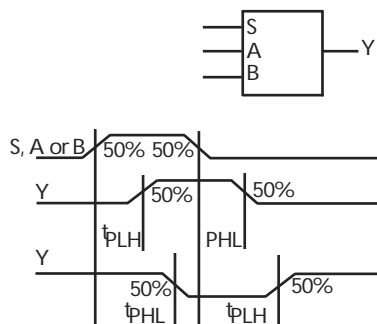
Note: Values are shown for 40MX –3 speed devices at 5.0 V worst-case commercial conditions.

Figure 18 • 42MX Timing Model



Note: 1. Input module predicted routing delay

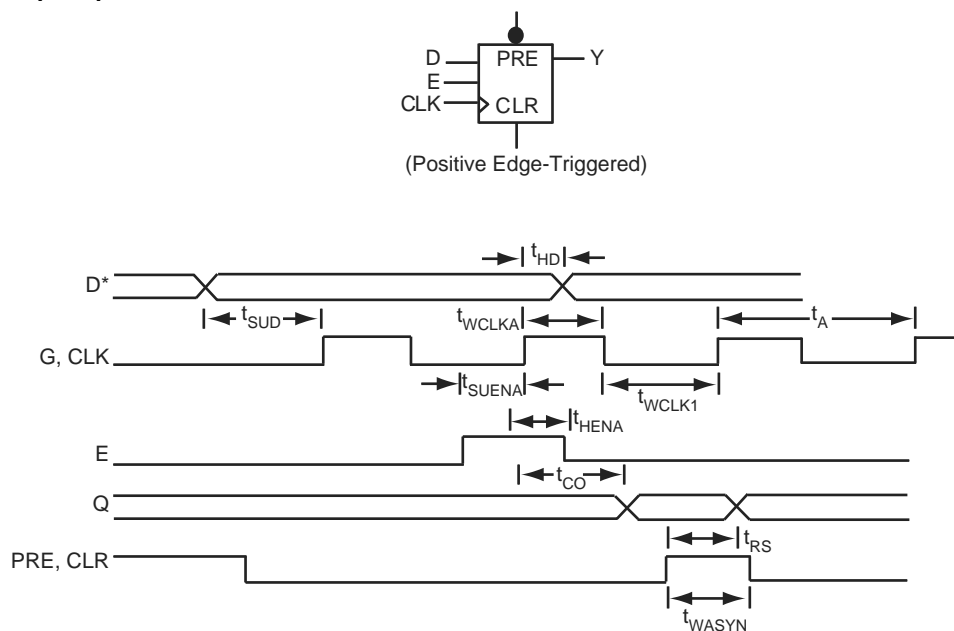
Note: 2. Values are shown for A42MX09 –3 at 5.0 V worst-case commercial conditions.

Figure 22 • AC Test Loads**Figure 23 • Input Buffer Delays****Figure 24 • Module Delays**

3.10.2 Sequential Module Timing Characteristics

The following figure shows sequential module timing characteristics.

Figure 25 • Flip-Flops and Latches



Note: *D represents all data functions involving A, B, and S for multiplexed flip-flops.

3.10.3 Sequential Timing Characteristics

The following figures show sequential timing characteristics.

Figure 26 • Input Buffer Latches

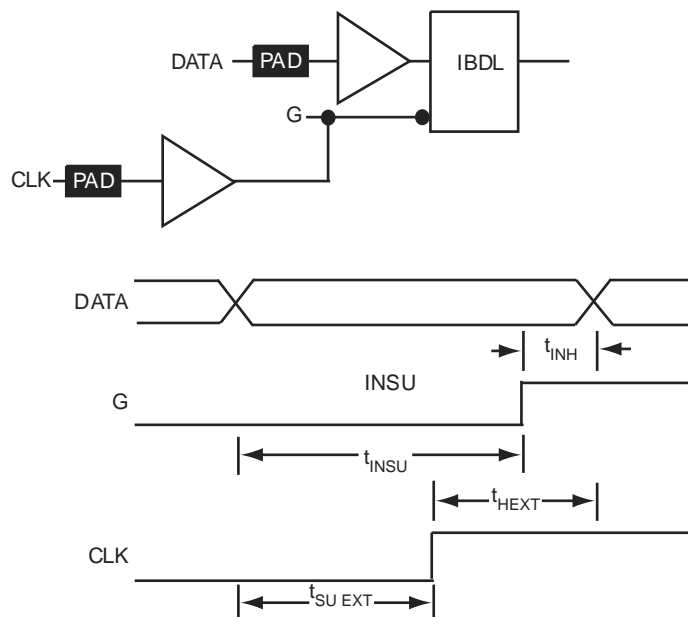
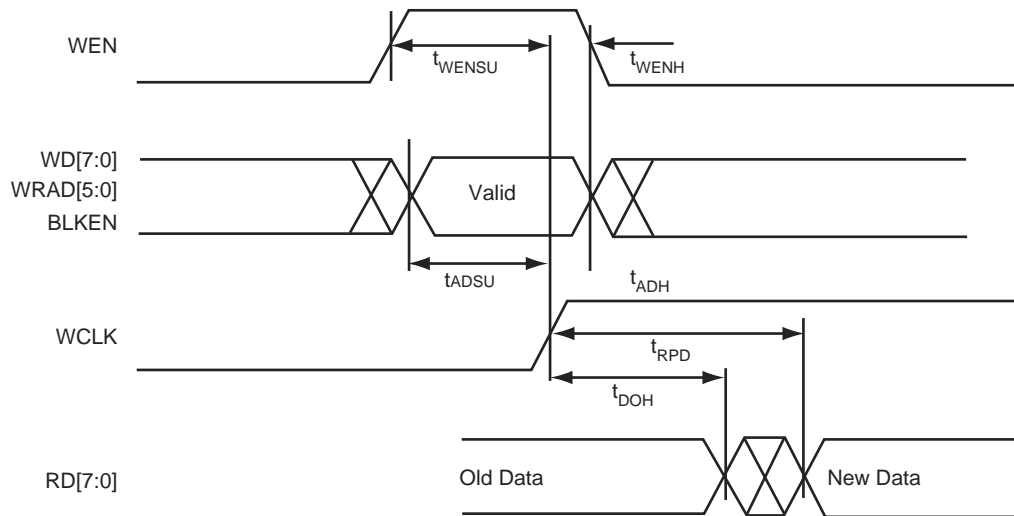


Figure 33 • 42MX SRAM Asynchronous Read Operation—Type 2 (Write Address Controlled)

3.10.7 Predictable Performance: Tight Delay Distributions

Propagation delay between logic modules depends on the resistive and capacitive loading of the routing tracks, the interconnect elements, and the module inputs being driven. Propagation delay increases as the length of routing tracks, the number of interconnect elements, or the number of inputs increases.

From a design perspective, the propagation delay can be statistically correlated or modeled by the fanout (number of loads) driven by a module. Higher fanout usually requires some paths to have longer routing tracks.

The MX FPGAs deliver a tight fanout delay distribution, which is achieved in two ways: by decreasing the delay of the interconnect elements and by decreasing the number of interconnect elements per path.

Microsemi's patented antifuse offers a very low resistive/capacitive interconnect. The antifuses, fabricated in 0.45 μm lithography, offer nominal levels of 100 Ω resistance and 7.0 fF capacitance per antifuse.

MX fanout distribution is also tight due to the low number of antifuses required for each interconnect path. The proprietary architecture limits the number of antifuses per path to a maximum of four, with 90 percent of interconnects using only two antifuses.

3.11 Timing Characteristics

Device timing characteristics fall into three categories: family-dependent, device-dependent, and design-dependent. The input and output buffer characteristics are common to all MX devices. Internal routing delays are device-dependent; actual delays are not determined until after place-and-route of the user's design is complete. Delay values may then be determined by using the Designer software utility or by performing simulation with post-layout delays.

3.11.1 Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most timing critical paths. Critical nets are determined by net property assignment in Microsemi's Designer software prior to placement and routing. Up to 6% of the nets in a design may be designated as critical.

3.11.2 Long Tracks

Some nets in the design use long tracks, which are special routing resources that span multiple rows, columns, or modules. Long tracks employ three and sometimes four antifuse connections, which increase capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically, up to 6 percent of nets in a fully utilized device require long tracks. Long tracks add

approximately a 3 ns to a 6 ns delay, which is represented statistically in higher fanout (FO=8) routing delays in the data sheet specifications section, shown in Table 34, page 41.

3.11.3 Timing Derating

MX devices are manufactured with a CMOS process. Therefore, device performance varies according to temperature, voltage, and process changes. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature and worst-case processing.

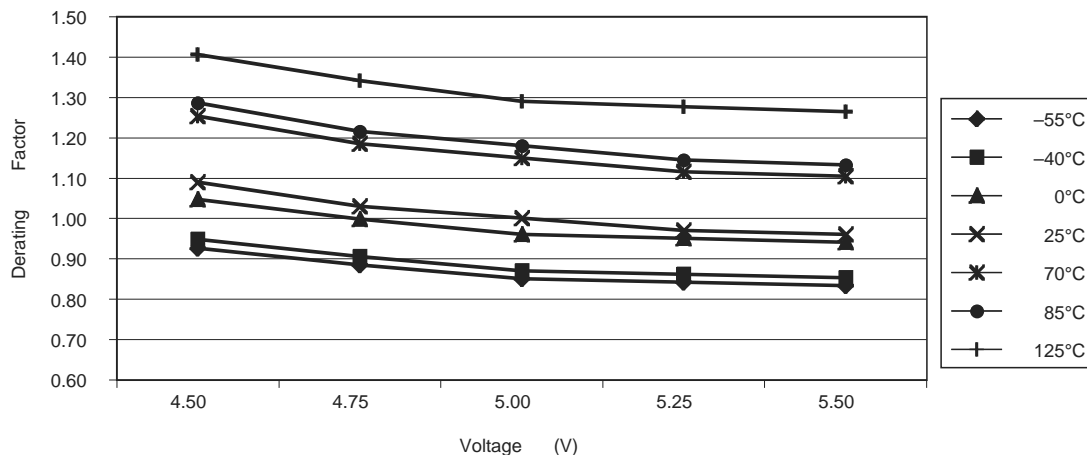
3.11.4 Temperature and Voltage Derating Factors

The following tables and figures show temperature and voltage derating factors for 40MX and 42MX FPGAs.

Table 28 • 42MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 5.0\text{ V}$)

42MX Voltage	Temperature						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
4.50	0.93	0.95	1.05	1.09	1.25	1.29	1.41
4.75	0.88	0.90	1.00	1.03	1.18	1.22	1.34
5.00	0.85	0.87	0.96	1.00	1.15	1.18	1.29
5.25	0.84	0.86	0.95	0.97	1.12	1.14	1.28
5.50	0.83	0.85	0.94	0.96	1.10	1.13	1.26

Figure 34 • 42MX Junction Temperature and Voltage Derating Curves (Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 5.0\text{ V}$)



Note: This derating factor applies to all routing and propagation delays

Table 29 • 40MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^\circ\text{C}$, $V_{CC} = 5.0\text{ V}$)

40MX Voltage	Temperature						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
4.50	0.89	0.93	1.02	1.09	1.25	1.31	1.45
4.75	0.84	0.88	0.97	1.03	1.18	1.24	1.37
5.00	0.82	0.85	0.94	1.00	1.15	1.20	1.33
5.25	0.80	0.82	0.91	0.97	1.12	1.16	1.29
5.50	0.79	0.82	0.90	0.96	1.10	1.15	1.28

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		3.4		3.8		5.5		6.4		9.0	ns
t _{DHL}	Data-to-Pad LOW		4.1		4.5		4.2		5.0		7.0	ns
t _{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.6		5.5		7.6	ns
t _{ENZL}	Enable Pad Z to LOW		4.1		4.5		5.1		6.1		8.5	ns
t _{ENHZ}	Enable Pad HIGH to Z		6.9		7.6		8.6		10.2		14.2	ns
t _{ENLZ}	Enable Pad LOW to Z		7.5		8.3		9.4		11.1		15.5	ns
t _{GLH}	G-to-Pad HIGH		5.8		6.5		7.3		8.6		12.0	ns
t _{GHL}	G-to-Pad LOW		5.8		6.5		7.3		8.6		12.0	ns
t _{LSU}	I/O Latch Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.7		9.7		10.9		12.9		18.0	ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		12.2		13.5		15.4		18.1		25.3	ns
d _{TLH}	Capacity Loading, LOW to HIGH		0.04		0.04		0.05		0.06		0.08	ns/pF
d _{THL}	Capacity Loading, HIGH to LOW		0.05		0.05		0.06		0.07		0.10	ns/pF

1. For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

Table 40 • A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays ¹												
t _{PD1}	Single Module		1.4		1.5		1.7		2.0		2.8	ns
t _{CO}	Sequential Clock-to-Q		1.4		1.6		1.8		2.1		3.0	ns
t _{GO}	Latch G-to-Q		1.4		1.5		1.7		2.0		2.8	ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q		1.6		1.7		2.0		2.3		3.3	ns
Logic Module Predicted Routing Delays ²												
t _{RD1}	FO = 1 Routing Delay		0.8		0.9		1.0		1.2		1.6	ns
t _{RD2}	FO = 2 Routing Delay		1.0		1.2		1.3		1.5		2.1	ns

Table 40 • A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing ⁴												
t _{DLH}	Data-to-Pad HIGH	2.5		2.8		3.2		3.7		5.2		ns
t _{DHL}	Data-to-Pad LOW	3.0		3.3		3.7		4.4		6.1		ns
t _{ENZH}	Enable Pad Z to HIGH	2.7		3.0		3.4		4.0		5.6		ns
t _{ENZL}	Enable Pad Z to LOW	3.0		3.3		3.8		4.4		6.2		ns
t _{ENHZ}	Enable Pad HIGH to Z	5.4		6.0		6.8		8.0		11.2		ns
t _{ENLZ}	Enable Pad LOW to Z	5.0		5.6		6.3		7.4		10.4		ns
t _{GLH}	G-to-Pad HIGH	2.9		3.2		3.6		4.3		6.0		ns
t _{GHL}	G-to-Pad LOW	2.9		3.2		3.6		4.3		6.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading	5.7		6.3		7.1		8.4		11.9		ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading	8.0		8.9		10.1		11.9		16.7		ns
d _{TLH}	Capacitive Loading, LOW to HIGH	0.03		0.03		0.03		0.04		0.06		ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW	0.04		0.04		0.04		0.05		0.07		ns/pF

Table 41 • A42MX16 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Sequential Timing ^{3, 4}													
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up		0.5		0.5		0.6		0.7		0.9		ns
t _{HD}	Flip-Flop (Latch) Data Input Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up		1.0		1.1		1.2		1.4		2.0		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		4.8		5.3		6.0		7.1		9.9		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		6.2		6.9		7.9		9.2		12.9		ns
t _A	Flip-Flop Clock Input Period		9.5		10.6		12.0		14.1		19.8		ns
t _{INH}	Input Buffer Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Buffer Latch Set-Up		0.7		0.8		0.9		1.01		1.4		ns
t _{OUTH}	Output Buffer Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{OUTSU}	Output Buffer Latch Set-Up		0.7		0.8		0.89		1.01		1.4		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency			129		117		108		94		56	MHz
Input Module Propagation Delays													
t _{INYH}	Pad-to-Y HIGH			1.5		1.6		1.9		2.2		3.1	ns
t _{INYL}	Pad-to-Y LOW			1.1		1.3		1.4		1.7		2.4	ns
t _{INGH}	G to Y HIGH			2.0		2.2		2.5		2.9		4.1	ns
t _{INGL}	G to Y LOW			2.0		2.2		2.5		2.9		4.1	ns
Input Module Predicted Routing Delays ²													
t _{IRD1}	FO = 1 Routing Delay			2.6		2.9		3.2		3.8		5.3	ns
t _{IRD2}	FO = 2 Routing Delay			2.9		3.2		3.7		4.3		6.1	ns
t _{IRD3}	FO = 3 Routing Delay			3.3		3.6		4.1		4.9		6.8	ns
t _{IRD4}	FO = 4 Routing Delay			3.6		4.0		4.6		5.4		7.6	ns
t _{IRD8}	FO = 8 Routing Delay			5.1		5.6		6.4		7.5		10.5	ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 32	4.4		4.8		5.5		6.5		9.0	ns	
		FO = 384	4.8		5.3		6.0		7.1		9.9	ns	
t _{CKL}	Input HIGH to LOW	FO = 32	5.3		5.9		6.7		7.8		11.0	ns	
		FO = 384	6.2		6.9		7.9		9.2		12.9	ns	
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	5.7		6.3		7.1		8.4		11.8	ns	
		FO = 384	6.6		7.4		8.3		9.8		13.7	ns	

Figure 39 • PL68

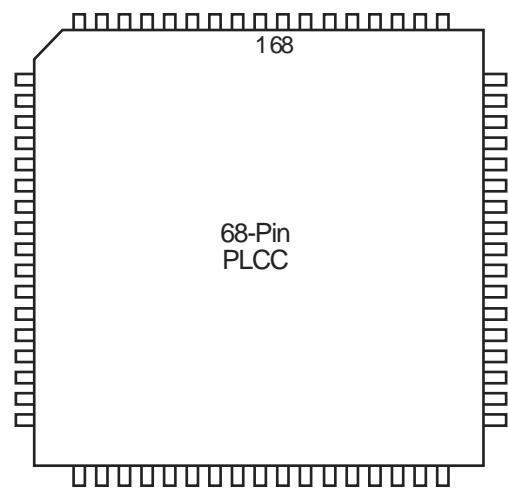


Table 48 • PL68

PL68		
Pin Number	A40MX02 Function	A40MX04 Function
1	I/O	I/O
2	I/O	I/O
3	I/O	I/O
4	VCC	VCC
5	I/O	I/O
6	I/O	I/O
7	I/O	I/O
8	I/O	I/O
9	I/O	I/O
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	GND	GND
15	GND	GND
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	I/O	I/O
21	VCC	VCC
22	I/O	I/O
23	I/O	I/O

Table 49 • PL84

PL84				
Pin Number	A40MX04 Function	A42MX09 Function	A42MX16 Function	A42MX24 Function
10	I/O	DCLK, I/O	DCLK, I/O	DCLK, I/O
11	I/O	I/O	I/O	I/O
12	NC	MODE	MODE	MODE
13	I/O	I/O	I/O	I/O
14	I/O	I/O	I/O	I/O
15	I/O	I/O	I/O	I/O
16	I/O	I/O	I/O	I/O
17	I/O	I/O	I/O	I/O
18	GND	I/O	I/O	I/O
19	GND	I/O	I/O	I/O
20	I/O	I/O	I/O	I/O
21	I/O	I/O	I/O	I/O
22	I/O	VCCA	VCCI	VCCI
23	I/O	VCCI	VCCA	VCCA
24	I/O	I/O	I/O	I/O
25	VCC	I/O	I/O	I/O
26	VCC	I/O	I/O	I/O
27	I/O	I/O	I/O	I/O
28	I/O	GND	GND	GND
29	I/O	I/O	I/O	I/O
30	I/O	I/O	I/O	I/O
31	I/O	I/O	I/O	I/O
32	I/O	I/O	I/O	I/O
33	VCC	I/O	I/O	I/O
34	I/O	I/O	I/O	TMS, I/O
35	I/O	I/O	I/O	TDI, I/O
36	I/O	I/O	I/O	WD, I/O
37	I/O	I/O	I/O	I/O
38	I/O	I/O	I/O	WD, I/O
39	I/O	I/O	I/O	WD, I/O
40	GND	I/O	I/O	I/O
41	I/O	I/O	I/O	I/O
42	I/O	I/O	I/O	I/O
43	I/O	VCCA	VCCA	VCCA
44	I/O	I/O	I/O	WD, I/O
45	I/O	I/O	I/O	WD, I/O
46	VCC	I/O	I/O	WD, I/O

Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
58	I/O	WD, I/O	WD, I/O
59	I/O	I/O	I/O
60	VCCI	VCCI	VCCI
61	NC	I/O	I/O
62	NC	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	QCLKA, I/O
66	I/O	WD, I/O	WD, I/O
67	NC	WD, I/O	WD, I/O
68	NC	I/O	I/O
69	I/O	I/O	I/O
70	I/O	WD, I/O	WD, I/O
71	I/O	WD, I/O	WD, I/O
72	I/O	I/O	I/O
73	I/O	I/O	I/O
74	I/O	I/O	I/O
75	I/O	I/O	I/O
76	I/O	I/O	I/O
77	I/O	I/O	I/O
78	GND	GND	GND
79	VCCA	VCCA	VCCA
80	NC	VCCI	VCCI
81	I/O	I/O	I/O
82	I/O	I/O	I/O
83	I/O	I/O	I/O
84	I/O	I/O	I/O
85	I/O	WD, I/O	WD, I/O
86	I/O	WD, I/O	WD, I/O
87	I/O	I/O	I/O
88	I/O	I/O	I/O
89	NC	I/O	I/O
90	NC	I/O	I/O
91	I/O	I/O	QCLKB, I/O
92	I/O	I/O	I/O
93	I/O	WD, I/O	WD, I/O
94	I/O	WD, I/O	WD, I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
15	QCLKC, I/O
16	I/O
17	WD, I/O
18	WD, I/O
19	I/O
20	I/O
21	WD, I/O
22	WD, I/O
23	I/O
24	PRB, I/O
25	I/O
26	CLKB, I/O
27	I/O
28	GND
29	VCCA
30	VCCI
31	I/O
32	CLKA, I/O
33	I/O
34	PRA, I/O
35	I/O
36	I/O
37	WD, I/O
38	WD, I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	I/O
45	QCLKD, I/O
46	I/O
47	WD, I/O
48	WD, I/O
49	I/O
50	I/O
51	I/O

Table 56 • VQ100

VQ100		
Pin Number	A42MX09 Function	A42MX16 Function
21	I/O	I/O
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	I/O	I/O
26	I/O	I/O
27	I/O	I/O
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	GND	GND
33	I/O	I/O
34	I/O	I/O
35	I/O	I/O
36	I/O	I/O
37	I/O	I/O
38	VCCA	VCCA
39	I/O	I/O
40	I/O	I/O
41	I/O	I/O
42	I/O	I/O
43	I/O	I/O
44	GND	GND
45	I/O	I/O
46	I/O	I/O
47	I/O	I/O
48	I/O	I/O
49	I/O	I/O
50	SDO, I/O	SDO, I/O
51	I/O	I/O
52	I/O	I/O
53	I/O	I/O
54	I/O	I/O
55	GND	GND
56	I/O	I/O

Table 56 • VQ100

VQ100		
Pin Number	A42MX09 Function	A42MX16 Function
57	I/O	I/O
58	I/O	I/O
59	I/O	I/O
60	I/O	I/O
61	I/O	I/O
62	LP	LP
63	VCCA	VCCA
64	VCCI	VCCI
65	VCCA	VCCA
66	I/O	I/O
67	I/O	I/O
68	I/O	I/O
69	I/O	I/O
70	GND	GND
71	I/O	I/O
72	I/O	I/O
73	I/O	I/O
74	I/O	I/O
75	I/O	I/O
76	I/O	I/O
77	SDI, I/O	SDI, I/O
78	I/O	I/O
79	I/O	I/O
80	I/O	I/O
81	I/O	I/O
82	GND	GND
83	I/O	I/O
84	I/O	I/O
85	PRA, I/O	PRA, I/O
86	I/O	I/O
87	CLKA, I/O	CLKA, I/O
88	VCCA	VCCA
89	I/O	I/O
90	CLKB, I/O	CLKB, I/O
91	I/O	I/O
92	PRB, I/O	PRB, I/O

Table 58 • CQ208

CQ208	
Pin Number	A42MX36 Function
1	GND
2	VCCA
3	MODE
4	I/O
5	I/O
6	I/O
7	I/O
8	I/O
9	I/O
10	I/O
11	I/O
12	I/O
13	I/O
14	I/O
15	I/O
16	I/O
17	VCCA
18	I/O
19	I/O
20	I/O
21	I/O
22	GND
23	I/O
24	I/O
25	I/O
26	I/O
27	GND
28	VCCI
29	VCCA
30	I/O
31	I/O
32	VCCA
33	I/O
34	I/O
35	I/O
36	I/O

Figure 53 • CQ172

Table 62 • CQ172

CQ172	
Pin Number	A42MX16 Function
1	MODE
2	I/O
3	I/O
4	I/O
5	I/O
6	I/O
7	GND
8	I/O
9	I/O
10	I/O
11	I/O
12	VCC
13	I/O
14	I/O
15	I/O
16	I/O
17	GND
18	I/O
19	I/O
20	I/O